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Kind regards,

Team Nexperia



# PBSS305ND

# 100 V, 3 A NPN low V<sub>CEsat</sub> (BISS) transistor Rev. 02 — 7 December 2007

**Product data sheet** 

### **Product profile**

### 1.1 General description

NPN low V<sub>CEsat</sub> Breakthrough In Small Signal (BISS) transistor in a SOT457 (SC-74) small Surface-Mounted Device (SMD) plastic package.

PNP complement: PBSS305PD.

#### 1.2 Features

- Low collector-emitter saturation voltage V<sub>CEsat</sub>
- High collector current capability I<sub>C</sub> and I<sub>CM</sub>
- High collector current gain (h<sub>FE</sub>) at high I<sub>C</sub>
- High efficiency due to less heat generation
- Smaller required Printed-Circuit Board (PCB) area than for conventional transistors

### 1.3 Applications

- High-voltage DC-to-DC conversion
- High-voltage MOSFET gate driving
- High-voltage motor control
- High-voltage power switches (e.g. motors, fans)
- Thin Film Transistor (TFT) backlight inverter
- Automotive applications

#### 1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
$V_{CEO}$	collector-emitter voltage	open base		-	-	100	V
I <sub>C</sub>	collector current		[1]	-	-	3	Α
$I_{CM}$	peak collector current	single pulse; $t_p \le 1 \text{ ms}$		-	-	4	Α
R <sub>CEsat</sub>	collector-emitter saturation resistance	$I_C = 2 A;$ $I_B = 200 \text{ mA}$	[2]	-	73	95	mΩ

<sup>[1]</sup> Device mounted on a ceramic PCB, Al<sub>2</sub>O<sub>3</sub>, standard footprint.



<sup>[2]</sup> Pulse test:  $t_p \le 300 \ \mu s; \ \delta \le 0.02.$ 

# 2. Pinning information

Table 2. Pinning

	3		
Pin	Description	Simplified outline	Symbol
1	collector	D- D- D-	
2	collector	<u> </u>	1, 2, 5, 6 
3	base	0	3 —
4	emitter	1 12 13	1
5	collector		sym014
6	collector		5,

# 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PBSS305ND	SC-74	plastic surface-mounted package (TSOP6); 6 leads	SOT457

# 4. Marking

Table 4. Marking codes

Type number	Marking code
PBSS305ND	AG

**Product data sheet** 

# 5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

	_				
Symbol	Parameter	Conditions	Min	Max	Unit
$V_{CBO}$	collector-base voltage	open emitter	-	100	V
$V_{CEO}$	collector-emitter voltage	open base	-	100	V
$V_{EBO}$	emitter-base voltage	open collector	-	5	V
I <sub>C</sub>	collector current		<u>[1]</u> _	1	Α
			[2] _	3	Α
I <sub>CM</sub>	peak collector current	single pulse; $t_p \le 1 \text{ ms}$	-	4	Α
$I_B$	base current		-	8.0	Α
I <sub>BM</sub>	peak base current	single pulse; $t_p \le 1 \text{ ms}$	-	2	Α
P <sub>tot</sub>	total power dissipation	T <sub>amb</sub> ≤ 25 °C	<u>[1]</u> _	360	mW
			[3]	600	mW
			<u>[4]</u> _	750	mW
			[2] _	1.1	W
			[1][5]	2.5	W
Tj	junction temperature		-	150	°C
T <sub>amb</sub>	ambient temperature		-65	+150	°C
T <sub>stg</sub>	storage temperature		-65	+150	°C

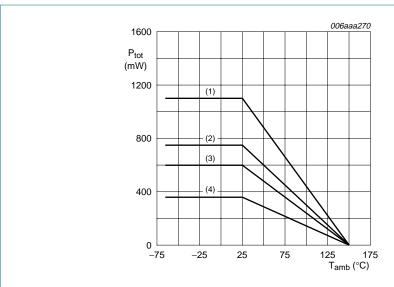
<sup>[1]</sup> Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.

<sup>[2]</sup> Device mounted on a ceramic PCB, Al<sub>2</sub>O<sub>3</sub>, standard footprint.

<sup>[3]</sup> Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 1 cm<sup>2</sup>.

<sup>[4]</sup> Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 6 cm<sup>2</sup>.

<sup>[5]</sup> Pulse test:  $t_p \le 10$  ms;  $\delta \le 10$  %.



- (1) Ceramic PCB, Al<sub>2</sub>O<sub>3</sub>, standard footprint
- (2) FR4 PCB, mounting pad for collector 6 cm<sup>2</sup>
- (3) FR4 PCB, mounting pad for collector 1 cm<sup>2</sup>
- (4) FR4 PCB, standard footprint

Fig 1. Power derating curves

#### Thermal characteristics 6.

Table 6. **Thermal characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from	in free air	<u>[1]</u> -	-	350	K/W
	junction to ambient		[2] _	-	208	K/W
			[3] _	-	167	K/W
			<u>[4]</u> _	-	113	K/W
			[1][5]	-	113 50	K/W
$R_{th(j-sp)}$	thermal resistance from junction to solder point		-	-	45	K/W

- [1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 1 cm<sup>2</sup>.
- Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for collector 6 cm<sup>2</sup>.
- Device mounted on a ceramic PCB, Al<sub>2</sub>O<sub>3</sub>, standard footprint.
- [5] Pulse test:  $t_p \le 10$  ms;  $\delta \le 10$  %.

**Product data sheet** 

100 V, 3 A NPN low V<sub>CEsat</sub> (BISS) transistor

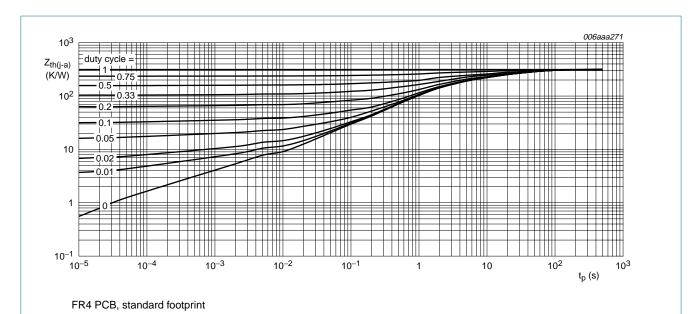


Fig 2. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

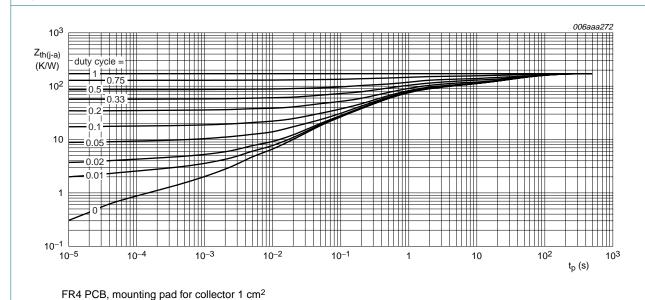


Fig 3. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

100 V, 3 A NPN low V<sub>CEsat</sub> (BISS) transistor

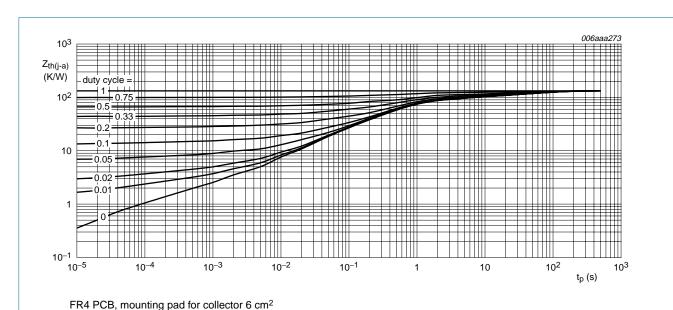
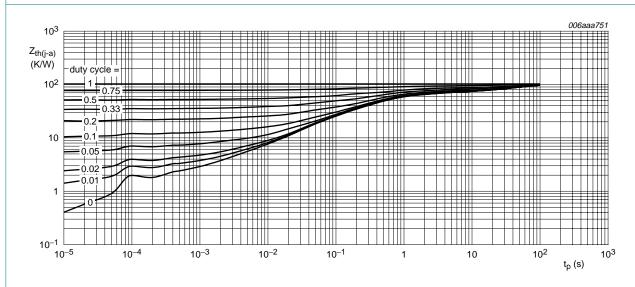


Fig 4. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values



Ceramic PCB, Al<sub>2</sub>O<sub>3</sub>, standard footprint

Fig 5. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

100 V, 3 A NPN low V<sub>CEsat</sub> (BISS) transistor

#### **Characteristics 7**.

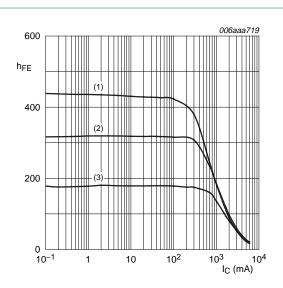
Table 7. **Characteristics** 

 $T_{amb} = 25 \,^{\circ}C$  unless otherwise specified.

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
I <sub>CBO</sub>	collector-base cut-off	$V_{CB} = 100 \text{ V}; I_E = 0 \text{ A}$		-	-	100	nA
	current	$V_{CB} = 100 \text{ V}; I_E = 0 \text{ A};$ $T_j = 150 \text{ °C}$		-	-	50	μΑ
I <sub>CES</sub>	collector-emitter cut-off current	$V_{CE} = 80 \text{ V}; V_{BE} = 0 \text{ V}$		-	-	100	nA
I <sub>EBO</sub>	emitter-base cut-off current	$V_{EB} = 5 \text{ V}; I_{C} = 0 \text{ A}$		-	-	100	nA
h <sub>FE</sub>	DC current gain	$V_{CE} = 2 \text{ V}; I_{C} = 0.5 \text{ A}$		170	275	-	
		V <sub>CE</sub> = 2 V; I <sub>C</sub> = 1 A	[1]	125	185	-	
		$V_{CE} = 2 \text{ V}; I_{C} = 2 \text{ A}$	<u>[1]</u>	70	95	-	
		$V_{CE} = 2 \text{ V}; I_{C} = 3 \text{ A}$	[1]	40	55	-	
		V <sub>CE</sub> = 2 V; I <sub>C</sub> = 4 A	[1]	25	40	-	
$V_{CEsat}$	collector-emitter	$I_C = 0.5 \text{ A}; I_B = 50 \text{ mA}$		-	45	60	mV
	saturation voltage	I <sub>C</sub> = 1 A; I <sub>B</sub> = 50 mA		-	90	120	mV
		I <sub>C</sub> = 2 A; I <sub>B</sub> = 200 mA	[1]	-	145	190	mV
		$I_C = 3 A$ ; $I_B = 150 mA$	<u>[1]</u>	-	240	310	mV
		I <sub>C</sub> = 3 A; I <sub>B</sub> = 300 mA	[1]	-	215	280	mV
		I <sub>C</sub> = 4 A; I <sub>B</sub> = 400 mA	[1]	-	280	360	
R <sub>CEsat</sub>	collector-emitter saturation resistance	$I_C = 2 \text{ A}; I_B = 200 \text{ mA}$	[1]	-	73	95	mΩ
$V_{BEsat}$	base-emitter saturation voltage	$I_C = 0.5 \text{ A}; I_B = 50 \text{ mA}$		-	0.79	0.87	V
		$I_C = 1 \text{ A}; I_B = 50 \text{ mA}$		-	0.81	0.89	V
		I <sub>C</sub> = 1 A; I <sub>B</sub> = 100 mA	[1]	-	0.83	0.92	V
		I <sub>C</sub> = 3 A; I <sub>B</sub> = 150 mA	[1]	-	0.93	0.99	V
		$I_C = 3 \text{ A}; I_B = 300 \text{ mA}$	[1]	-	0.95	1.02	V
$V_{BEon}$	base-emitter turn-on voltage	$V_{CE} = 2 \text{ V}; I_C = 2 \text{ A}$		-	0.83	1	V
t <sub>d</sub>	delay time	$V_{CC} = 9.2 \text{ V}; I_C = 2 \text{ A};$		-	14	-	ns
t <sub>r</sub>	rise time	$I_{Bon} = 0.1 \text{ A}; I_{Boff} = -0.1 \text{ A}$		-	341	-	ns
t <sub>on</sub>	turn-on time			-	355	-	ns
t <sub>s</sub>	storage time			-	246	-	ns
t <sub>f</sub>	fall time			-	343	-	ns
t <sub>off</sub>	turn-off time			-	589	-	ns
f⊤	transition frequency	$V_{CE} = 10 \text{ V}; I_{C} = 100 \text{ mA};$ f = 100 MHz		-	140	-	MHz
C <sub>c</sub>	collector capacitance	$V_{CB} = 10 \text{ V}; I_E = I_e = 0 \text{ A};$ f = 1 MHz		-	16	-	pF

<sup>[1]</sup> Pulse test:  $t_p \le 300~\mu s;~\delta \le 0.02.$ 

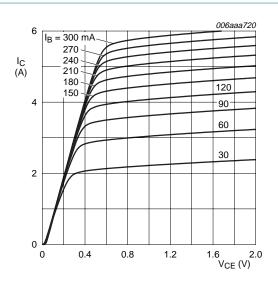
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$$V_{CE} = 2 V$$

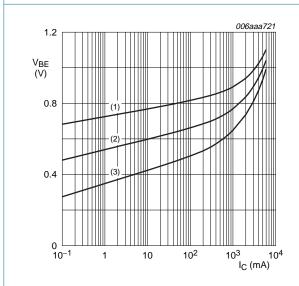
- (1)  $T_{amb} = 100 \, ^{\circ}C$
- (2)  $T_{amb} = 25 \, ^{\circ}C$
- (3)  $T_{amb} = -55 \, ^{\circ}C$

Fig 6. DC current gain as a function of collector current; typical values



 $T_{amb} = 25 \, ^{\circ}C$ 

Fig 7. Collector current as a function of collector-emitter voltage; typical values

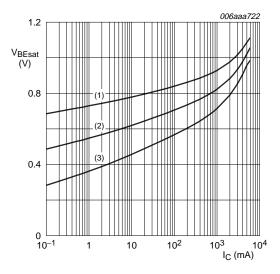




- (1)  $T_{amb} = -55 \,^{\circ}C$
- (2)  $T_{amb} = 25 \, ^{\circ}C$
- (3)  $T_{amb} = 100 \, ^{\circ}C$

**Product data sheet** 

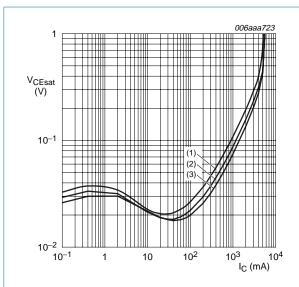
Fig 8. Base-emitter voltage as a function of collector current; typical values



$$I_{\rm C}/I_{\rm B} = 20$$

- (1)  $T_{amb} = -55 \,^{\circ}C$
- (2)  $T_{amb} = 25 \, ^{\circ}C$
- (3)  $T_{amb} = 100 \, ^{\circ}C$

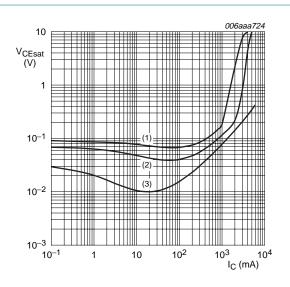
Fig 9. Base-emitter saturation voltage as a function of collector current; typical values



$$I_{\rm C}/I_{\rm B} = 20$$

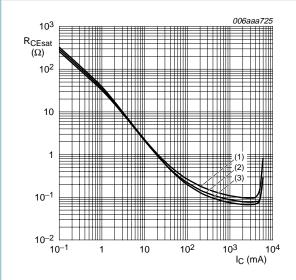
- (1)  $T_{amb} = 100 \, ^{\circ}C$
- (2)  $T_{amb} = 25 \,^{\circ}C$
- (3)  $T_{amb} = -55 \,^{\circ}C$

Fig 10. Collector-emitter saturation voltage as a function of collector current; typical values



- (1)  $I_C/I_B = 100$
- (2)  $I_C/I_B = 50$
- (3)  $I_C/I_B = 10$

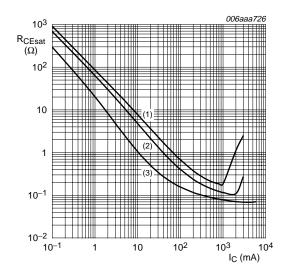
Fig 11. Collector-emitter saturation voltage as a function of collector current; typical values



- $I_{\rm C}/I_{\rm B} = 20$
- (1)  $T_{amb} = 100 \, ^{\circ}C$
- (2)  $T_{amb} = 25 \,^{\circ}C$
- (3)  $T_{amb} = -55 \, ^{\circ}C$

**Product data sheet** 

Fig 12. Collector-emitter saturation resistance as a function of collector current; typical values



- (1)  $I_C/I_B = 100$
- (2)  $I_C/I_B = 50$
- (3)  $I_C/I_B = 10$

Fig 13. Collector-emitter saturation resistance as a function of collector current; typical values

100 V, 3 A NPN low V<sub>CEsat</sub> (BISS) transistor

# **Test information**

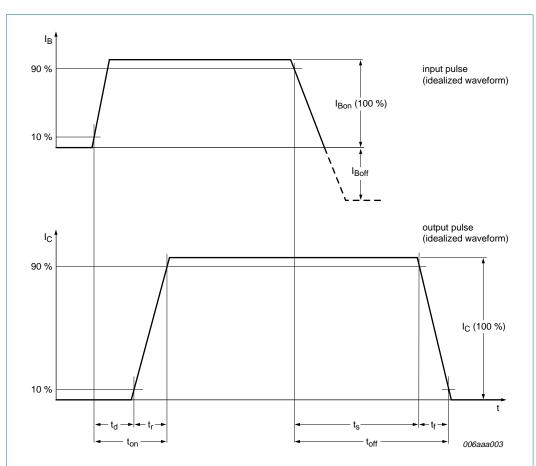


Fig 14. BISS transistor switching time definition

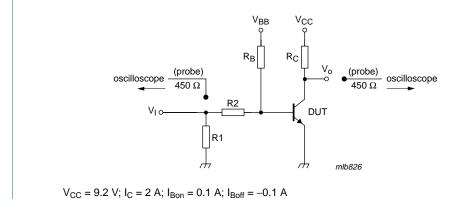
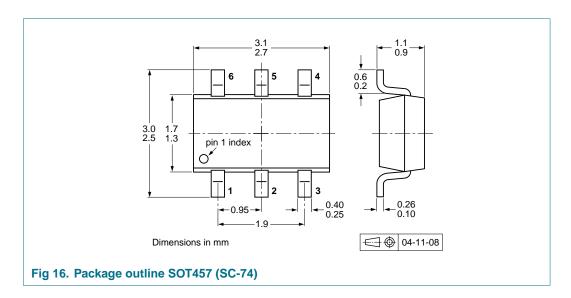


Fig 15. Test circuit for switching times

# 9. Package outline



# 10. Packing information

Table 8. Packing methods

The indicated -xxx are the last three digits of the 12NC ordering code.[1]

Type number	Package	Description		Packing qu	uantity
				3000	10000
PBSS305ND	SOT457	4 mm pitch, 8 mm tape and reel; T1	[2]	-115	-135
		4 mm pitch, 8 mm tape and reel; T2	[3]	-125	-165

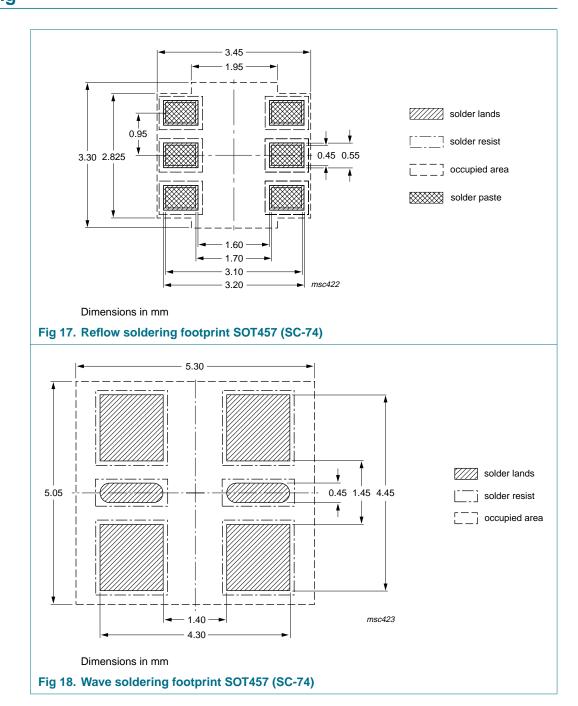
[1] For further information and the availability of packing methods, see  $\underline{\text{Section 14}}$ .

[2] T1: normal taping

[3] T2: reverse taping

100 V, 3 A NPN low V<sub>CEsat</sub> (BISS) transistor

# 11. Soldering





# 12. Revision history

#### Table 9. **Revision history**

Document ID	Release date	Data sheet status	Change notice	Supersedes		
PBSS305ND_2	20071207	Product data sheet	-	PBSS305ND_1		
Modifications:		f this data sheet has been red NXP Semiconductors.	esigned to comply w	ith the new identity		
	<ul> <li>Legal texts have been adapted to the new company name where appropriate.</li> </ul>					
	<ul> <li><u>Table 6</u>: typir</li> </ul>	ng error for maximum value on	6 cm <sup>2</sup> footprint ame	nded		
	<ul> <li>Section 13 "L</li> </ul>	<u>egal information"</u> : updated				
PBSS305ND_1	20060410	Product data sheet	-	-		

# 13. Legal information

#### 13.1 **Data sheet status**

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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# PBSS305ND

### 100 V, 3 A NPN low V<sub>CEsat</sub> (BISS) transistor

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